

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,140,832	10-2000	Vu et al.	324/765
	C	US-			
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	M	US-			

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	X	Thibeault, "Improving Delta-IDDQ-based test methods," IEEE International Test Conference Proceedings, 3-5 Oct. 2000, pp. 207-206.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.